OE750



Ultimate quality control. No compromise.



High performance and efficiency

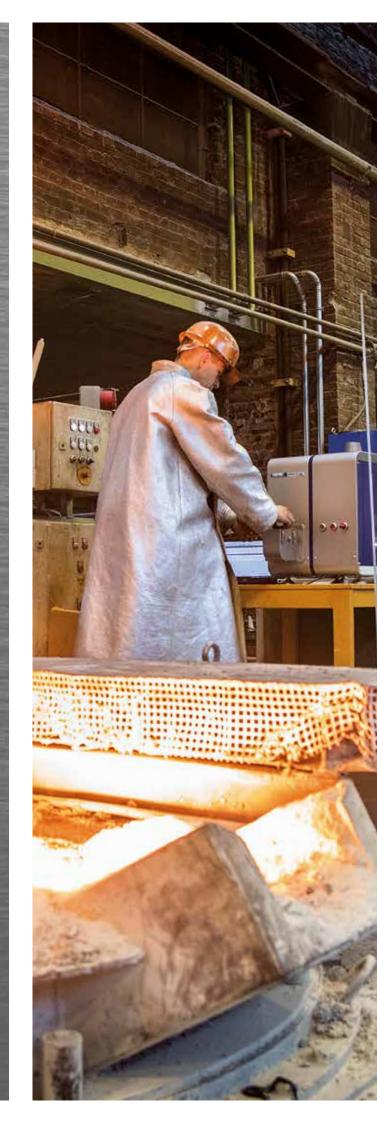
The OE750 is a ground-breaking new OES metals analyser. Covering the complete spectrum of elements in metal, it also has low detection limits.

Tightening of industry regulations, complex supply chains and increased use of scrap as a base material means it's crucial for foundries and metals manufacturers to control tramp and trace elements in the lowest ppm range. Historically, OES analysis at this level was out of reach for many businesses. That's now changed with the OE750 from Hitachi High-Tech.

This brand-new spark spectrometer allows you to analyse all main alloying elements and identify exceptionally low levels of tramp, trace and treatment elements in metals, such as nitrogen in steel. Fast measurement times, high reliability and low operating costs mean the OE750 is invaluable for everyday analysis and total quality control, with performance on a par with larger and more expensive spectrometers.

There are over 45 years of metals industry experience behind the design of the German-made OE750. From measuring nitrogen in steel and iron to phosphorus in aluminium, this analyser gives you the comprehensive metals analysis you need to meet today's tough specifications.

For fast, comprehensive metals quality analysis in a single affordable instrument, the OE750 from Hitachi High-Tech delivers everything you need.





Why choose the OE750?

RESULTS YOU CAN TRUST

High optical resolution to control tramp and trace elements.

LOW COST OF OWNERSHIP

Affordable to buy and run, delivering the performance of more expensive analysers.

KEEPING YOU RUNNING

Engineered for reliability with minimum maintenance and standardisation requirements.

SUPPORTS CONTINUOUS PRODUCTION

Rapid analysis and short start-up times for fast feedback on melt quality.



How we make high-performance affordable

IT'S ALL DOWN TO THE TECHNOLOGY.

The OE750 includes state of the art semiconductor detectors and a new optical concept (with four patents pending). This gives the Hitachi OES analyser high optical resolution, so you don't have to choose between high performance and low cost.

Innovative use of dynamic CMOS detectors and direct coupling of the optics to the spark-stand ensures the best luminosity together with a wavelength range of 119 nm to 766 nm. This covers all elements, from hydrogen to uranium, for complete metals analysis*. This performance is usually only available with high end quality control instrumentation, yet the OE750 keeps costs down through innovation, low argon and power consumption.

The OE750 gives you maximum flexibility for element selection, making your operation fit for the future.

MAXIMUM RELIABILITY MINIMUM DOWNTIME

- The OE750 is engineered to keep you running. Maintenance time is minimised; for example you only need to clean the spark stand every few thousand measurements* and standardisation intervals are typically weeks, or even months. This could potentially buy you up to two hours of extra productivity.
- Plus, a newly developed electrical spark source gives you better reliability and the best energy excitation pulse per element, making your analysis more precise.

*Depending on the application, for further details request our application reports

Software innovation to support quality control

SPARCFIRE

The modern operating software for the OE750 with a state-of-the-art user interface is designed to meet the requirements of metallurgical experts but is intuitive enough to be operated by inexperienced users.

GRADE DATABASE

The largest metals database on the market for fast and easy grade identification is pre-installed on the OE750. The Hitachi GRADE Database offers more than 15 million records for over 350,000 materials from over 70 countries and standards. You can update your instrument's grade database with a few clicks – no time-consuming research in norms and grade catalogues.

CHARGE CORRECTION

This optional software automatically calculates the right quantity of material to add to a melt to bring it into spec. You no longer have to rely on human expertise and it greatly speeds up the charge correction process. The software also calculates the most cost-effective way to correct the melt by considering your available source material and furnace capacity.

STATISTICAL PROCESS CONTROL

The optional SPC allows you to easily monitor your processes and notifies you if your melt process or instrument is out of spec. You can set an upper and lower control limit for each element and see a visual representation of each element within those limits over time. This means you can reduce scrap and rework by spotting trends before they impact the final specification. On top of this, traceability functionality makes it easy to provide information for customer or regulatory audits.

EXTOPE CONNECT

ExTOPE Connect is an advanced data management and storage service that allows you to store your results safely, share data instantly and access data in real time from any computer. It includes unlimited free and secure data storage and you can manage a fleet of instruments across several sites from one centralised location.



Technical specifications





Dimensions, electrics

Width / height / depth

Weight

Power

Consumption max.

Operating mode / standby

425 mm / 535 mm / 760 mm

82 kg / 181 lbs

100 - 240 V AC, 50 / 60 Hz

430 W

45 W / (50 W source on)

Optical system

Rowland circle

High resolution multi-CMOS

Wavelength range

Focal length

Paschen-Runge mounting

Optimised pixel resolution

119 - 766 nm

400 mm

Solid state source

Frequency

Voltage

Computer controlled parameters

80 - 1000 Hz

250 - 500 V

High Energy Pre Spark (HEPS)

Readout system

External PC workstation

Microsoft® Windows® user interface

Options

Adapters

Spare parts kit

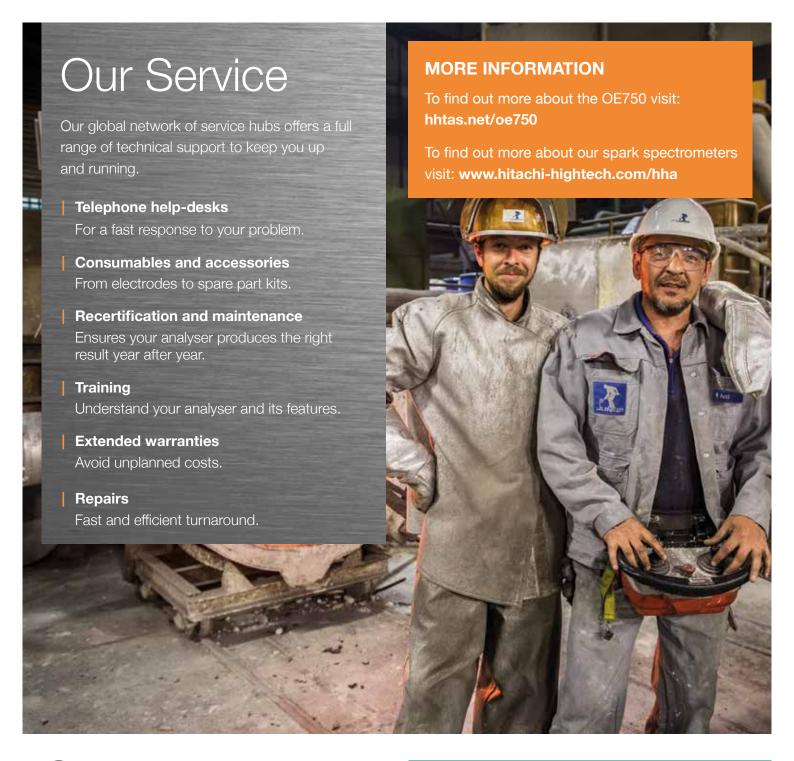
Consumables

Sample preparation devices

Floor stand version







Other products

We've been providing industrial analysis products for the manufacturing industry for over 45 years.

- Handheld LIBS: latest technology for 1-second alloy identification with no X-rays.
- Handheld XRF: for fast, reliable, non-destructive identification and analysis of alloys.

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Part number: 10023241







